

Notice of References Cited	Application/Control No. 10/684,579	Applicant(s)/Patent Under Reexamination FITZMAURICE ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,246,411	06-2001	Strauss, Randolph A.	715/863
*	B	US-2001/0009428	07-2001	Dow et al.	345/854
*	C	US-6,549,219	04-2003	Selker, Edwin J	715/834
*	D	US-5,634,064	05-1997	Warnock et al.	715/513
*	E	US-6,865,719	03-2005	Nicholas, III, James J.	715/856
*	F	US-5,638,523	06-1997	Mullet et al.	715/855
*	G	US-5,276,795	01-1994	Hoeber et al.	715/813
*	H	US-6,097,387	08-2000	Sciammarella et al.	715/784
*	I	US-6,938,221	08-2005	Nguyen, Vu	715/863
*	J	US-6,369,837	04-2002	Schirmer, Andrew L.	715/764
*	K	US-2002/0101458	08-2002	SanGiovanni, John	345/863
*	L	US-6,918,091	07-2005	Leavitt et al.	715/765
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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